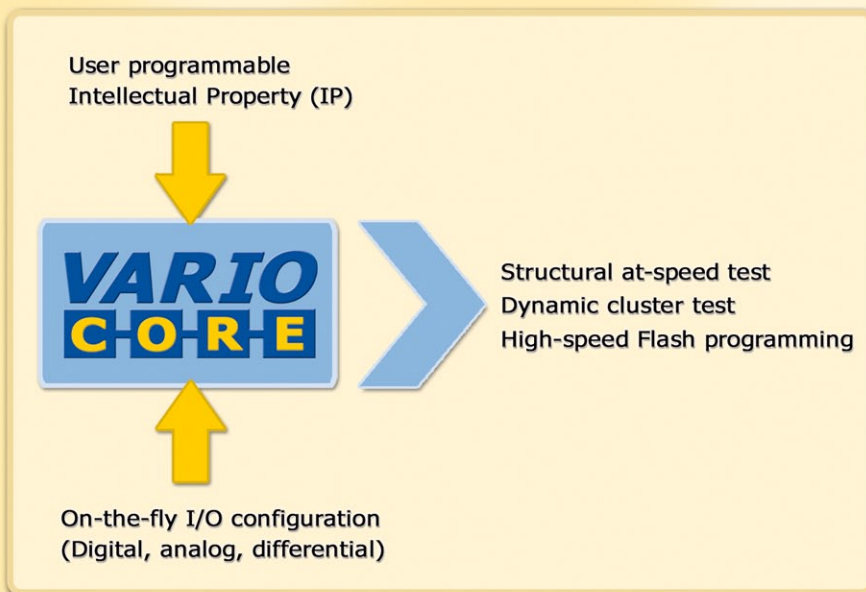
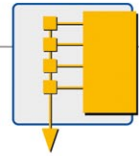


# VarioCore® Technology for SCANFLEX® I/O Modules



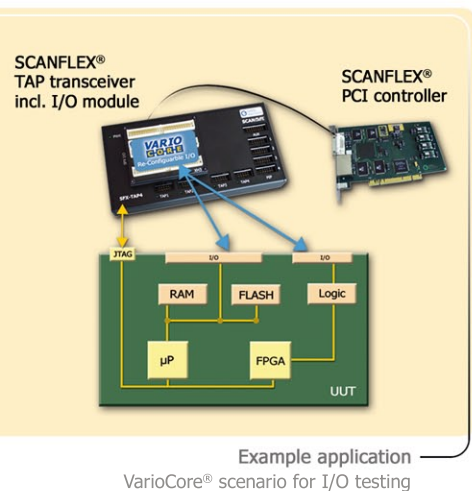
VarioCore® enables users to dynamically change I/O functionality using standard, custom functions or other Intellectual Property (IP). It is an open architecture technology supporting static and dynamic signal processing, and is programmable using off-the-shelf tools.

VarioCore® does not impose any restrictions on the sequence of re-configurations within a single test run.

The I/O modules are adaptable to a multitude of test, verification and programming applications including JTAG/Boundary Scan and functional test.

## Key Features

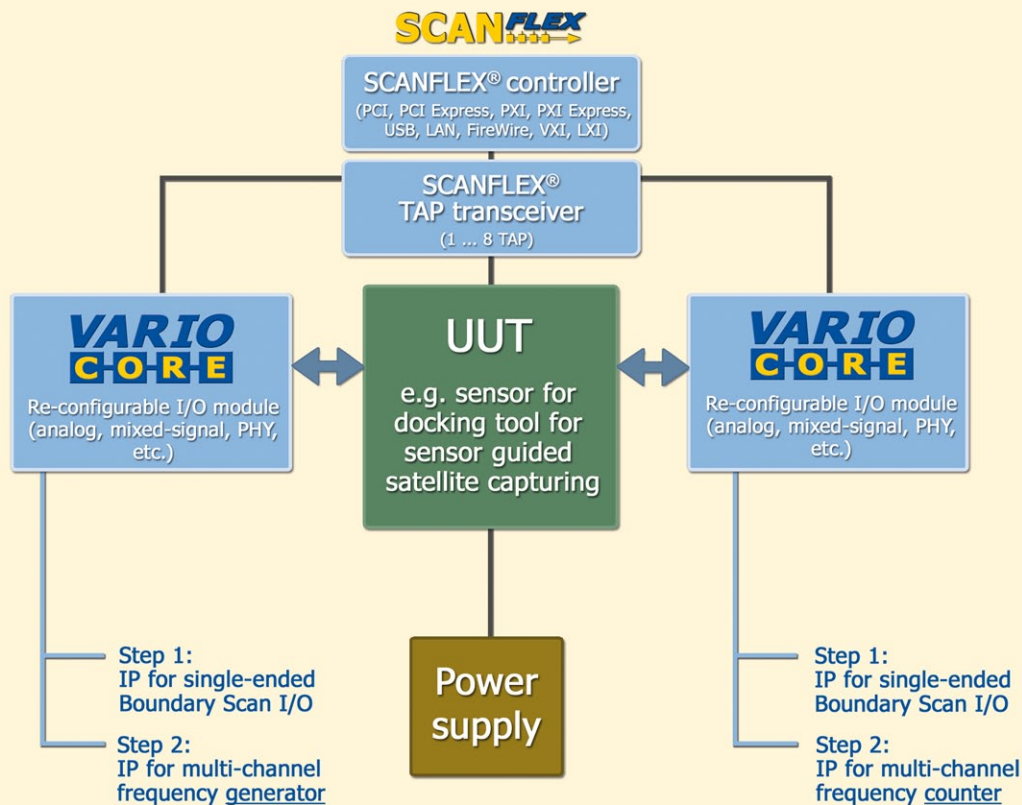
- Integrated technology for Extended JTAG/Boundary Scan interface testing
- Functional and at-speed testing of non-Boundary Scan devices and interfaces
- Faster deployment of programs and cost savings by using a single module
- On the fly reconfiguration
- Extension of SYSTEM CASCON™ and integrated with **SCANFLEX**
- No additional hardware required



## VarioCore® - Next Generation I/O Module Architecture for SCANFLEX®

Applying IP (Intellectual Property) based functionality (example: frequency measurement) from an integrated software environment provides a new level of flexibility. For example, a digital VarioCore® module can support a wide variety of static and dynamic test, verification and programming applications, synchronised with JTAG/Boundary Scan or stand-alone.

This enables at-speed test, high-speed programming of serial and parallel EEPROM devices (e.g. Flash), and serial and parallel interface testing at functional speed.



Dynamic structural tests based on synthetic test instrumentation:

- Structural at-speed tests
- Dynamic cluster test
- High-speed Flash programming